



Designation: E902 – 05

Standard Practice for Checking the Operating Characteristics of X-Ray Photoelectron Spectrometers¹

This standard is issued under the fixed designation E902; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ε) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This practice covers a procedure for checking some of the operating characteristics of an X-ray photoelectron spectrometer. Tests herein provide checks of the repeatability of intensity measurements and the drift of the intensities with time. This practice may be conducted at the same time as the spectrometer energy calibration using Practice E2108.

1.2 *Limitations*—This practice is meant to augment, and not to replace, the calibration procedures recommended by the manufacturer of the spectrometer. This practice is also not meant to be used as a means of comparison between X-ray photoelectron spectrometers, but only as a self-consistent check of the operating characteristics of an individual spectrometer.

1.3 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.*

2. Referenced Documents

2.1 ASTM Standards:²

- E673 Terminology Relating to Surface Analysis
- E996 Practice for Reporting Data in Auger Electron Spectroscopy and X-ray Photoelectron Spectroscopy
- E1078 Guide for Specimen Preparation and Mounting in Surface Analysis
- E2108 Practice for Calibration of the Electron Binding-Energy Scale of an X-Ray Photoelectron Spectrometer

2.2 ISO Standards

ISO 21270 Surface Chemical Analysis — X-ray Photoelectron and Auger Electron Spectrometers – Linearity of Intensity Scale

ISO 24237 Surface Chemical Analysis— X-ray Photoelectron Spectroscopy – Repeatability and Constancy of Intensity Scale

3. Terminology

3.1 *Definitions*—Terms used in X-ray photoelectron spectroscopy are defined in Terminology E673.

3.2 Additionally, the following terms and abbreviations are used throughout this practice:

c	= counts
ch	= channel
cps	= counts per second
eV	= electron volts
i	= number of data channels acquired for the peak of interest
n	= number of channels
no.	= number of
S/B	= signal-to-background ratio
sc	= span
Δx	= step size, eV, between successive data channels
A	= peak area above background, mm ²
B	= background height, mm
H	= maximum peak height above background, mm
I _A	= peak area intensity above background, c-eV/s
I _H	= maximum signal intensity above background, cps
P	= peak position on the binding energy scale, eV
FWHM	= full width at half maximum

4. Significance and Use

4.1 This practice should first be used to establish the operating characteristics of a particular X-ray photoelectron spectrometer at a time when the spectrometer performance is known to be optimum. Hence, the spectrometer settings in Section 5 and the expected performance figures given in Section 7 are to be taken only as guides, to be supplanted by the behavior of the user's actual spectrometer.

¹ This practice is under the jurisdiction of ASTM Committee E42 on Surface Analysis and is the direct responsibility of Subcommittee E42.03 on Auger Electron Spectroscopy and X-Ray Photoelectron Spectroscopy.

Current edition approved April 1, 2005. Published April 2005. Originally approved in 1982. Last previous edition approved in 1999 as E902 – 94 (1999). DOI: 10.1520/E0902-05.

² For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.

4.3 Typical analysis settings should be used with this practice. The use of settings not specified by this practice is left to the discretion of the user, however, the settings should be recorded in accordance with Practice E996 and the same settings should be used consistently whenever this practice is repeated, so that the results obtained will be directly comparable to previous results.

5.1 Obtain the Reference Sample—Use a copper reference sample; the sample shall be polycrystalline and with a purity of at least 99.8 %. The sample can conveniently be a foil of typical dimensions 10 by 10 mm. The specimen should be larger than the analysis area of the spectrometer; the analysis area being defined as either the area viewed by the analyzer or the area of illumination of the X-ray beam, whichever is smaller. The thickness should be between 0.1 mm and 0.2 mm. A new copper gasket segment can also be used. If the Cu sample appears discolored, a short dip in 1 % nitric acid may be used to clean the surface with subsequent rinsing in distilled water. If the Cu sample has been stored in air for more than a few days, the cleaning with nitric acid will reduce the time needed for later sputter cleaning. Guide E1078 recommends additional specimen handling precautions that may be required.

5.3 Use an ion sputter gun to clean the specimen until the C1s and O1s peak heights above background are each less than or equal to 2 % of the Cu 3p peak height above background. If sputtering is not available, the intensities of the C1s and O1s peaks may exceed 10 % of the Cu 3p peak; in this case, record the C1s and O1s peak heights above background.

5.5 Acquire and store the photoelectron spectrum of the Cu 2p doublet between 963 and 923 eV, with enough scans to collect at least 10 000 counts at the peak maximum.

5.7 If using Mg X-rays, acquire and store the spectrum of the Cu $L_3M_{4,5}M_{4,5}$ Auger line between 340 and 330 eV (Note 1) on the binding energy scale. If using Al X-rays, acquire and store the spectrum of the Auger line between 573 and 563 eV

NOTE 1—For instruments where the minimum scan width is larger than recommended, use the minimum allowable scan width. For instruments where the energy interval cannot be set up in integer steps, use the closest allowed energy.

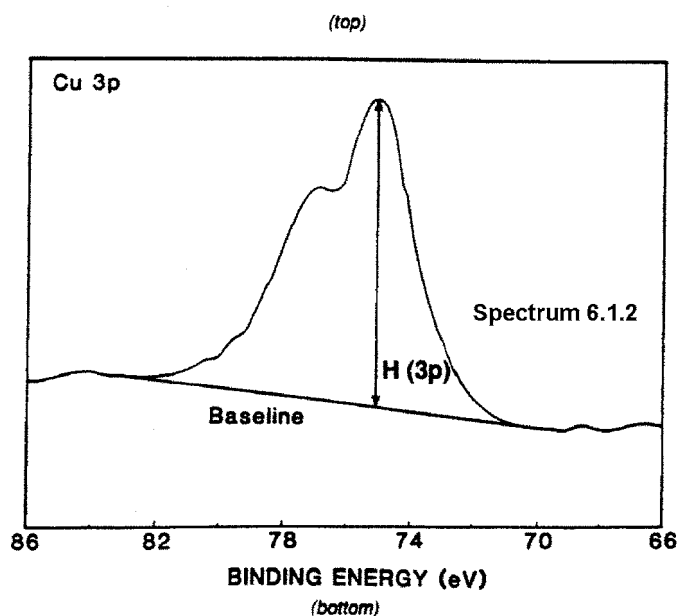
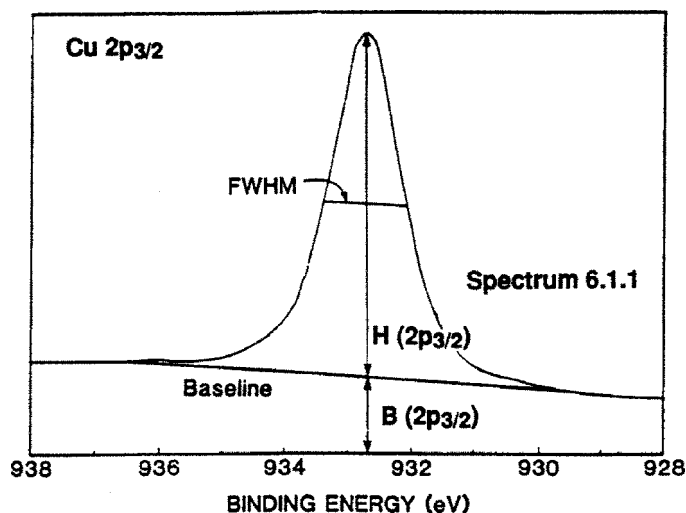
6.1 Print or plot the spectra as obtained in 5.5-5.7. In addition:

6.1.2 Print or plot the Cu $3p_{3/2}$ line between 86 and 66 binding energy.

NOTE 2—Some data-processing software packages automatically suppress the background, either when the data is collected or when it is displayed. The user should ensure that the background has not been altered before making the background measurement. Information about the treatment of backgrounds for a particular instrument can often be obtained by contacting the manufacturer of the software package or indirectly by comparison of computer-acquired data with analog data acquired with the same instrument settings over the same energy range.

6.2.2 If possible, use peak fitting algorithms to measure and record P , in electronvolts, for each spectrum and the FWHM, in electronvolts, for spectrum 6.1.1, as shown in Fig. 1. For an accurate comparison to the standard binding energies in Table 1, note that for the Cu 3p doublet there is fit to a quadratic to the top 10 % of the most intense peak. It must be further noted that a curve fit or peak synthesis routine will likely yield results that differ slightly from that method. Whichever method is chosen, the same method should be used whenever this practice is repeated. If a peak fitting routine is not available, then accurately measure, compute, and record these values from the data outputs of spectra 6.1.1 and 6.1.2 as shown in Fig. 1.

7.1 Refer to Section 3 for definitions and abbreviations. For all peaks, record the signal intensity. If this information is not



NOTE 1—Spectral lines obtained in accordance with procedures in 6.1.1 (top) and 6.1.2 (bottom) illustrating the data treatments described in 6.2.

FIG. 1 Spectral Lines

TABLE 1 Reference Binding Energies, $E_{ref,n}$ for the Peaks Used in the Calibration Procedure for the Indicated X-Ray Sources (1,2)

NOTE 1—The Ag data included in parentheses are not used normally in the calibration

	$E_{ref,n}$ (eV)		
	Al $K\alpha$	Mg $K\alpha$	Monochromatic Al $K\alpha$
Au $4f_{7/2}$	83.95	83.95	83.96
Ag $3d_{5/2}$	(368.22)	(368.22)	368.21
Cu $3p$	75.14	75.13	...
Cu L_3 VV	567.93	334.90	...
Cu $2p_{3/2}$	932.63	932.62	932.62

directly available, determine the signal intensity for each peak, j , using one of the following equations:

$$I_{H(j)} = \frac{H(j) [c/mm(j)]}{[s/sc(j)] [no. sc(j)]} \quad (1)$$

or

$$I_{H(j)} = \frac{H(j) [c/mm(j)]}{[s/ch(j)] [no. ch/sc(j)] [no. sc(j)]} \quad (2)$$

7.2 Determine and record the signal-to-background ratio (S/B) for the Cu $2p_{3/2}$ line from spectrum 6.1.1 and data treatment 6.2 by:

$$S/B = H(2p_{3/2})/B(2p_{3/2}) \quad (3)$$

For most instruments with conventional X-ray sources, the S/B is typically between 4.0 and 5.0. For spectrometers equipped with monochromatic X-ray sources, this value is expected to be higher. For an abraded sample, this ratio will be expected to be lower because of surface roughness and the effects of greater contamination. A low ratio may indicate detection of excessive stray electrons or insufficient counting speed by the detector.

7.3 The FWHM determined in 6.2.2 is a measure of instrumental resolution and checks for freedom from short-term fluctuations in the voltage supplies that determine the electron kinetic energy. Changes in the FWHM are indicative of a spectrometer that needs maintenance or recalibration.

7.4 The area ratio can be used to determine the transmission ratio. The peak area intensity, I_A , for a given peak, j , can be computed by:

$$I_{A(j)} = \frac{A(j) [c/mm(j)] [eV/sc(j)]}{[s/sc(j)] [no. sc(j)] [mm/sc(j)]} \quad (4)$$

or

$$I_{A(j)} = \frac{A(j) [c/mm(j)] [eV/mm(j)]}{[s/sc(j)] [no. sc(j)] [no. ch/sc(j)]} \quad (5)$$

Record the ratio $I_{A(3p)}/I_{A(2p_{3/2})}$.

7.4.1 If a computer cannot be used to measure $A(j)$ or $I_{A(j)}$, other methods may be used. One common algorithm utilizes the trapezoidal rule, which reduces to

$$I_{A(j)} = \Delta x \sum_{i=1}^n I_{H(i)} \quad (6)$$

where the two endpoints = zero intensity.

7.4.1.1 Whichever method is chosen, it should be used consistently, since different methods may give different results.

7.4.2 For an instrument with transmission varying as (kinetic energy) $^{-1}$, the value of $I_{A(3p)}/I_{A(2p_{3/2})}$ has been determined on several instruments to be approximately 0.1. This value appears to be higher for abraded samples. For instruments with transmission varying as (kinetic energy) $^{+1}$, the ratio will be between 0.7 and 1.0.

7.4.3 The spectrometer transmission function can be determined using Cu, Au, and Ag specimens with commercially available calibration software (4)

7.5 Table 1 lists measurements of the copper peak positions (Refs 1-3).³ Practice E2108 should be used to calibrate the electron binding energy scale of an x-ray photoelectron spectrometer.

³ The boldface numbers in parentheses refer to the references at the end of this practice.

8. Conclusion

8.1 Most values obtained in this practice will be characteristic of a particular spectrometer and serve to demonstrate whether the instrument is performing reproducibly. A few data have been provided as a guide to the values to be expected. No attempt has been made here to supply voltage checks or individualized tests that may be supplied by instrument manufacturers.

8.2 These tests are conducted with a single material and have the advantage that accurate placement and treatment of two specimens is unnecessary. For those who wish also to use the Au 4f_{7/2} peak to check their instrument (in accordance with

Practice E2108, it must be emphasized that reproducible specimen positioning can have an influence on the determination of the relative binding energies measured for two specimens. For instruments with a monochromated Al X-ray source, a polycrystalline silver film of similar purity is also desirable as a reference specimen (see Practice E2108). The values of the Au 4f_{7/2} and Ag 3d_{5/2} binding energies are also reported in Table 1.

9. Keywords

9.1 spectrometer calibration; spectrometer characterization; X-ray photoelectron spectroscopy

REFERENCES

- (1) Seah, M. P., Gilmore, I. S., and Beamson, G., "XPS: Binding energy Calibration of Electron Spectrometers: 5 – Re-evaluation of the Reference Energies," *Surface and Interface Analysis*, Vol 26, No. 9, 1998, pp. 642–649.
- (2) Seah, M. P. and Gilmore, I. S., "AES: Energy calibration of Electron Spectrometers: III – General calibration Rules," *Journal of Electron Spectroscopy*, Vol 83, Nos. 2, 3, 1997, pp. 197–208.
- (3) Seah, M. P., *Surface and Interface Analysis*, Vol 14, 1989, p. 488.
- (4) NPL XPS Calibration Software, www.npl.co.uk/mamoanalysis, National Physical Laboratory, Hampton Rd., Teddington, Middlesex, UK, TW11 0LW.

ASTM International takes no position respecting the validity of any patent rights asserted in connection with any item mentioned in this standard. Users of this standard are expressly advised that determination of the validity of any such patent rights, and the risk of infringement of such rights, are entirely their own responsibility.

This standard is subject to revision at any time by the responsible technical committee and must be reviewed every five years and if not revised, either reapproved or withdrawn. Your comments are invited either for revision of this standard or for additional standards and should be addressed to ASTM International Headquarters. Your comments will receive careful consideration at a meeting of the responsible technical committee, which you may attend. If you feel that your comments have not received a fair hearing you should make your views known to the ASTM Committee on Standards, at the address shown below.

This standard is copyrighted by ASTM International, 100 Barr Harbor Drive, PO Box C700, West Conshohocken, PA 19428-2959, United States. Individual reprints (single or multiple copies) of this standard may be obtained by contacting ASTM at the above address or at 610-832-9585 (phone), 610-832-9555 (fax), or service@astm.org (e-mail); or through the ASTM website (www.astm.org).